

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10591206	IKEDA, MASAYUKI
	Examiner	Art Unit
	Nguyen, Hai V	2618

SEARCHED

Class	Subclass	Date	Examiner
455	553.1	03/07/2008	HN

SEARCH NOTES

Search Notes	Date	Examiner
EAST search (US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB) (See search history printout report)	03/12/2008	HN

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner